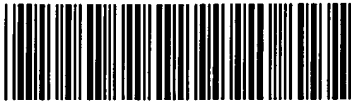


**Search Notes**

Application/Control No.

10/708,834

Examiner

Nam V. Nguyen

Applicant(s)/Patent under  
Reexamination

BEENAU ET AL.

Art Unit

2635

**SEARCHED**

Class	Subclass	Date	Examiner
340	5.53	5/22/2006	NN
340	5.2	5/22/2006	NN
340	5.4+	5/22/2006	NN
340	5.52	5/22/2006	NN
340	5.6	5/22/2006	NN
340	5.6+	5/22/2006	NN
340	10.1\	5/22/2006	NN
340	10.4-10.6	5/22/2006	NN
235	379	5/22/2006	NN
235	380	5/22/2006	NN
235	492	5/22/2006	NN
705	35,54,76	5/22/2006	NN
705	185	5/22/2006	NN
705	194	5/22/2006	NN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search: USPAT; US-PUB; EPO; JPO; and Derwent. (UPDATED SEARCH)	5/22/2006	NN